Dominating Interlayer Resonant Energy Transfer

in Type-II 2D Heterostructure

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ABSTRACT

Type-II heterostructures (HSs) are essential components of modern electronic and optoelectronic devices. Earlier studies have found that in type-II transition metal dichalcogenide (TMD) HSs, the dominating carrier relaxation pathway is the interlayer charge transfer (CT) mechanism. Here, this report shows that, in a type-II HS formed between monolayers of MoSe₂ and ReS₂, nonradiative energy transfer (ET) from higher to lower work function material (ReS₂ to MoSe₂) dominates over the traditional CT process with and *without* a charge-blocking interlayer. Without a charge-blocking interlayer, the HS area shows 3.6 times MoSe₂ photoluminescence (PL) enhancement as compared to the MoSe₂ area alone. In a completely encapsulated sample, the HS PL emission further increases by a factor of 6.4. After completely blocking the CT process, more than 1 order of magnitude higher MoSe₂ PL emission was achieved from the HS area. This work reveals that the nature of this ET is truly a resonant effect by showing that in a similar type-II HS formed by ReS₂ and WSe₂, CT dominates over ET, resulting in a severely quenched WSe₂ PL. This study not only provides significant insight into the competing interlayer processes but also shows an innovative way to increase the PL

emission intensity of the desired TMD material using ET process by carefully choosing the right material combination for HS.

KEYWORDS: energy transfer, charge transfer, photoluminescence, transition metal dichalcogenide, heterostructure

Energy transfer (ET) is a process in which energy is nonradiatively transferred from an excited fluorophore (donor) to another fluorophore (acceptor).^{1–3} ET is a long-range process without involving emission and reabsorption of photons.⁴ The ET theory is based on the concept considering an excited fluorophore as an oscillating dipole transferring energy to another dipole; similar as coupled pendulums in classical mechanics. We can use the following equation to describe the ET process from donor (D) to acceptor (A):

$$\boldsymbol{D}^* + \boldsymbol{A} \to \boldsymbol{D} + \boldsymbol{A}^* \tag{1}$$

where D^{*} and A^{*} are the excited states of the fluorophores. When donor and acceptor are in close proximity and donor emission spectra overlaps with the acceptor absorption spectra, the excited state energy from the donor gets transferred to the acceptor *via* dipole-dipole interaction and subsequently released in the form of radiative energy emission from the acceptor.^{2,3} ET, thus favorably occurs between parallel dipoles.³ ET has already been proven as the building block of many biological and chemical applications.^{5–8} Despite the long history of discovery,¹ ET exploration is still ongoing due to the fact that many promised applications are based on the idea of placing donor and acceptor in subnanometer proximity to fully utilize the ET process.⁹

Layered transition metal dichalcogenide (TMD) materials can be exfoliated down to atomically thin monolayers (1Ls), and the optical bandgaps of these materials spans the broad range of near-infrared to deep ultraviolet in the electromagnetic spectrum.¹⁰ Subnanometer spacing in heterostructures (HSs) created by stacking different van der Waals (vdW) materials

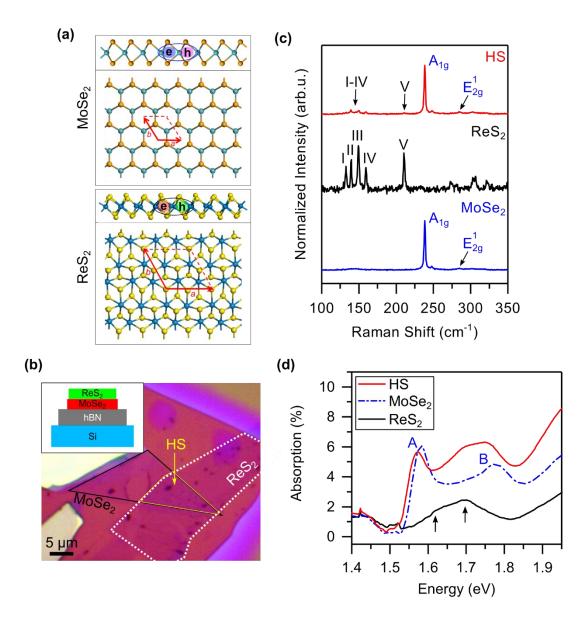


Figure 1. (a) Monolayer (1L) MoSe₂ and ReS₂ crystal structure. Top panels show the side view and bottom panels show the top view of the crystal structures. Side views show the schematic of in-plane orientation of dipoles across these layered materials. (b) Optical image of the ReS₂-MoSe₂ heterostructure from Sample 1 (S1). Inset is the schematic illustration of the sample's side view. (c) Raman spectra from the MoSe₂, ReS₂, and HS areas. HS Raman spectra consists of different vibrational modes from individual 1L area. (d) Absorption spectroscopy data of three different areas from a similar heterostructure made on a transparent sapphire substrate (Sample 2, S2). MoSe₂ A and B excitonic peaks are clearly visible, and ReS₂ lower energy absorption peaks are marked with arrows. HS spectra consists of peaks from both 1L areas.

has enabled opportunities to study exciting phenomena in 2D systems, such as Moiré patterns, valleytronics, spintronics and interlayer excitons just to mention a few.^{11–14} Thus, TMD HSs are ideal candidates to study the ET process because they can be stacked in atomically close

proximity. In TMD HSs, interlayer energy and charge transfer (CT) compete with each other; thus, comprehensive understanding of these processes is necessary to develop TMD-based applications.

The majority of the available TMD materials form type-II HSs.¹⁵ In traditional type-II TMD HSs, the dominating charge carrier relaxation pathway is interlayer CT process^{16–18} rather than interlayer ET mechanism. Kozawa *et al.*¹⁹ showed the presence of interlayer ET in type-II HS by placing an atomically thin charge-blocking layer, namely, a few-layer hexagonal boron nitride (hBN) in between the two TMD layers to suppress the interlayer CT process. Studying efficient ET process in TMD HSs requires materials with coinciding donor emission and acceptor absorption peak positions. Selection of the right TMD pairs is thus crucial to observing ET in type-II HSs.

A recent study²⁰ has predicted that a type-II HS formed between 1L rhenium disulfide (ReS₂) and 1L molybdenum diselenide (MoSe₂) integrated on a flexible substrate is an efficient candidate for near infrared (NIR) photodetection. Here, we experimentally study this HS and show that interlayer ET from ReS₂ to MoSe₂ dominates over the traditional interlayer CT process. As the donor, the emission of ReS₂ overlaps with the absorption of the acceptor, MoSe₂, and ReS₂ has a dominating nonradiative recombination channel. We show that the nonradiative ET from ReS₂ *resonantly* excites more carriers in MoSe₂ giving a 3.6 times enhanced PL emission from the HS even *without* having a charge-blocking layer in between the two materials. In a completely hBN encapsulated HS sample, we observe an increment of the HS PL emission by a factor of 6.4. By adding different thicknesses of hBN interlayer, we found that the PL enhancement, which is proportional to the ET, has a distance (d) dependence of ~1/d² at larger separation, indicating 2D dipole-2D dipole interaction between the TMD layers.²¹⁻²³ At a donor-acceptor separation of 13.5 nm, we successfully achieved 12.5 times higher MoSe₂ PL emission from the HS area by completely suppressing the other competing processes. We further show that, by replacing the MoSe₂ layer with 1L tungsten

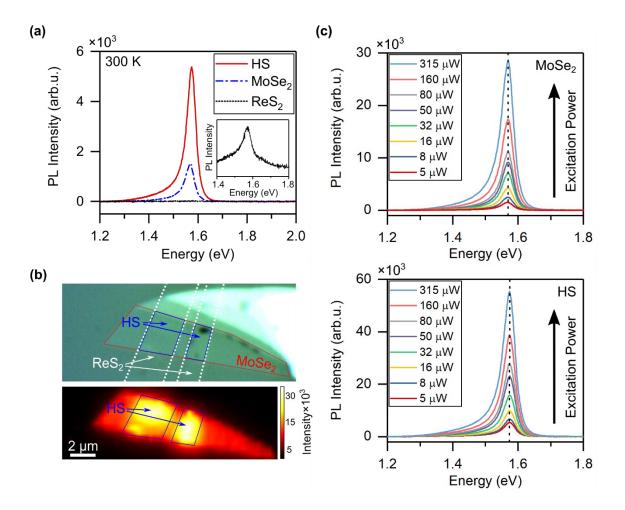


Figure 2. (a) Room temperature (RT) PL emission from the MoSe₂, ReS₂ and HS area of S1. Inset is the ReS₂ PL emission obtained at ~30 times higher laser power and longer accumulation. (b) Optical micrograph of another ReS₂-MoSe₂ HS, Sample 3 (S3) and PL intensity map from the same sample. The entire HS area shows this enhanced PL emission. (c) Laser power dependent PL from the MoSe₂ (top panel) and HS (bottom panel) area of S1. PL peak energy does not shift with increasing laser power, indicating that throughout the experiment we remain in material's linear regime.

diselenide (WSe₂), the resonant nature of ET breaks and interlayer CT dominates in the WSe₂-ReS₂ HS like other typical type-II HSs, exhibiting a severely quenched WSe₂ PL emission from the HS. This report shows that by carefully choosing the right material combination, we can interplay between the ET and CT processes and thus enhance the PL efficiency of the desired TMD material using resonant ET.

RESULTS AND DISCUSSION

The atomic arrangement of in-plane crystal structures of 1L MoSe₂ and 1L ReS₂ are shown in Figure 1(a), where the top and bottom panels of MoSe₂ (or ReS₂, respectively) show the side and top views of the materials. The side views also show the schematic illustration of the orientation of in-plane transition dipole moments in these layered materials. The MoSe₂ crystal structure has perfect in-plane 3-fold symmetry, whereas ReS₂ is an anisotropic material having triclinic crystal structure with an oblique in-plane lattice,^{24,25} as shown in Figure 1(a). 1L ReS₂-1L MoSe₂ HS samples were fabricated using micromechanical exfoliation (see the *Experimental Details*) and were stacked onto thick hBN layers to eliminate any effect from surface-mediated trap states during our experiment. Figure 1(b) shows the optical micrograph of the fabricated 1L ReS₂-1L MoSe₂ HS on hBN/Si substrate, namely Sample 1 (hereafter S1), where the inset shows a schematic illustration of the crosssection (stacking of layers) of the fabricated sample. The representative Raman spectra (Figure 1(c)) from the three different areas on S1 show MoSe₂ characteristics A_{1g} and E^{1}_{2g} peaks,^{26–28} ReS₂ intralayer modes (I-V),^{29,30} and the HS Raman spectra consisting of the characteristic peaks from both materials. It is also worth to note that in the HS Raman spectra, the signature peak positions of each material remain the same as compared to the individual monolayer area, suggesting a similar level of doping and strain in the HS area as compared to the monolayer areas.^{31,32} Figure 1(d) shows the absorption spectra from another HS made on a transparent sapphire substrate, Sample 2 (S2). We observed the characteristic A and B excitonic absorption from MoSe₂¹⁹ as well as two identifying absorption peaks in ReS₂ within close proximity³³ (pointed with arrows in Figure 1(d)). HS absorption spectrum consists of peaks from each layer and showed an overall higher optical absorption as compared to the monolayer areas. The slight redshift in the HS absorption peaks as compared to the MoSe₂ area could be due to the change in electronic coupling and dielectric environment.^{34,35} Room temperature (RT) PL peak position obtained from the MoSe₂ area of S1 matches well with previous published results 26,27,36 (Figure 2(a)). Being a pseudoindirect bandgap

semiconductor and having extremely low PL quantum yields, 1L ReS₂ has almost nonexistent PL emission^{33,37,38} (Figure 2(a)). To obtain analyzable signal-to-noise ratio in the ReS₂ PL spectrum, the laser excitation power required was ~30 times higher, and the accumulation time was much longer compared to the MoSe₂ and HS areas (inset of Figure 2(a)). It is important to observe that at RT, ReS₂ PL emission and MoSe₂ excitonic absorption peak position almost *coincided* with each other around 1.60 eV. Such a coincidence between the nonradiative and radiative excitonic bandgaps enables resonant ET to dominate, as discussed in later sections. Although 1L ReS₂ had slightly lower absorption than 1L MoSe₂ (Figure 1(d)), the almost nonexistent PL emission further proved that nonradiative recombination dominated in the 1L ReS₂ film. The Raman peak positions and strong (weak) PL intensity of MoSe₂ (ReS₂) prove their monolayer nature. The HS PL peak position perfectly matched with the MoSe₂ PL peak position, but the luminescence from the HS area was enhanced by a factor of ~3.6 as compared to the PL emission from the area of MoSe₂ alone (Figure 2(a)). The enhancement factor considered here is the ratio of the HS PL peak intensity to the MoSe₂ peak intensity, when the two area are excited by the same low illumination intensity and accumulation time. In order to check the distribution of this enhanced PL emission over the HS area, we collected a PL intensity map on a similar ReS2-MoSe2 HS, namely Sample 3 (hereafter S3) (Figure 2(b)) (see S.I. Figure S1 for the PL spectra of the sample). The red area in Figure 2(b) corresponds to the 1L MoSe₂ area. From the PL map, it is clear that the PL enhancement was not a localized phenomenon, but the entire HS area showed this enhanced PL emission at RT. We note that, although the PL emission was non-uniform within the HS area, due to impurities, wrinkles, cracks, and defects forming at the material boundary during the vacuum-annealing, the PL emission from the HS area was always larger than that from the 1L MoSe₂.

To further investigate the origin of this enhanced PL emission from the HS (S1), we performed low temperature (LT) PL measurement at 100 K (Figure S2). At LT, the HS still

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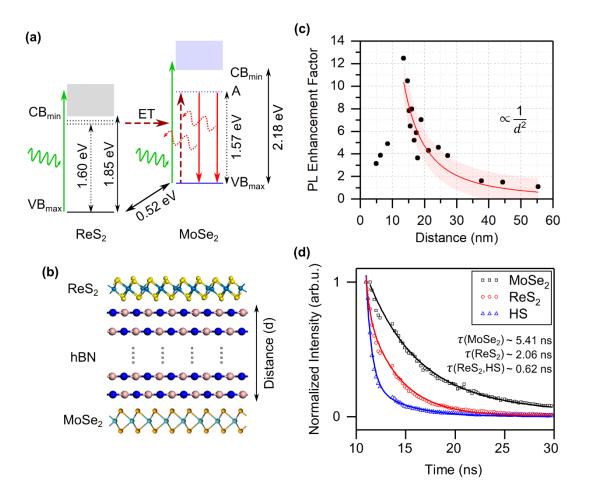


Figure 3. (a) Energy diagram representing the PL enhancement mechanism due to the resonance excitonic energy transfer from the ReS₂ to MoSe₂ layer. Excitonic levels are shown as dotted line below the conduction band minima. (b) Schematic illustration of the HS samples made with different thicknesses (distance) of hBN interlayer. (c) Change of PL enhancement from the HS area with distance. Pl enhancement factor shows 1/d² dependency at larger separation. (d) RT time resolved PL (TR-PL) spectra from the MoSe₂, ReS₂, and HS area of S3. Curve fitted data are shown by the solid line.

showed a similar PL enhancement factor of ~3, indicating that weakly temperature dependent dipole-dipole coupling dominated in this HS rather than the Dexter-type ET process (interlayer exciton transfer).^{19,39} Dexter- type ET can also be described using Equation 1, but the mechanism is different as discussed later. There is another possibility of the contribution of constructive interference from the back-reflected light at the sample-substrate interface as the origin of this enhanced PL emission.⁴⁰ However, we observed the HS PL enhancement in all of our samples irrespective of the different hBN substrate thicknesses, suggesting this interference was not a contributing factor. To further confirm this, we performed optical

transfer matrix method (TMM) calculations at different hBN thicknesses, and the results ruled out the possibility of any notable contribution from the optical interference effect in comparison to the observed PL enhancement (see S.I. for detailed discussion and Figure S3). Excitation power dependent PL measurements confirmed that we remained within the linear regimes of the materials (Figure 2(c)): for both the MoSe₂ and HS areas, the peak energy and full width at half maxima (FWHM) of the PL emission (Figure S4) remained unchanged with increasing excitation power. PL intensity shows sub-linear dependency with increasing laser power for both the MoSe₂ and HS area (Figure S5). This behavior suggests that defects/impurities affect the recombination mechanism in our samples,⁴¹ which is typical for annealed, exfoliated TMD samples. To check the effect of dielectric screening as the origin of this PL enhancement⁴² in the ReS₂-covered MoSe₂ layer, we fabricated an inverted MoSe₂-ReS₂ HS and observed similar PL enhancement (see Figure S6 for optical image and PL spectra of the sample), proving that dielectric screening had negligible effects in the PL enhancement process. After encapsulating the HS with a thin hBN top-layer, we further observed an overall increase in the HS PL emission by a factor of ~6.4 as compared to the encapsulated MoSe₂ area (Figure S7). We also exclude the possibilities of ET from hBN defects states⁴³ in our study (see S.I. for discussion and Figure S8-S9).

In order to experimentally determine the HS band-alignment type, we used Kelvin probe force microscopy (KPFM) to obtain the valence band (VB) offset (ΔE_V) between the MoSe₂ and ReS₂ layers as ~0.52 eV (Figure S10 and S11). Combining the experimental value of ΔE_V obtained from the KPFM measurement with the electronic bandgap,^{44,45} we determined that 1L ReS₂-1L MoSe₂ HS indeed form a type-II band alignment (Figure 3(a)) in agreement with earlier published theoretical works.^{15,20} This eliminated the possibility of short-range Dextertype ET in our system, as it requires the complete exciton to be transferred from donor to acceptor, which can be accomplished in type-I HSs.⁴⁶ In typical type-II HSs, the PL emission of both materials quench after forming the HS due to the interlayer CT process.^{16,17,19,47}

Interestingly the ReS₂-MoSe₂ HS, exhibited enhanced MoSe₂ PL emission from the HS area. We conclude that this enhancement was due to the ET process from the ReS₂ layer to the MoSe₂ layer. One possible reason of this unusual dominating ET process could be the suppression of coherent CT processes in this HS due to the weaker electronic coupling associated with symmetry mismatch and huge lattice mismatch between the trigonal in-plane of 2H-MoSe₂ and oblique in-plane of 1T-ReS₂ structure in comparison with the most studied 2H-TMD HSs. A recent ultrafast study on MoS2-ReS2 HS48 showed much slower photocarrier transfer time on the order of 1 ps, as compared to the ~100 fs CT time in the HS formed between 2H-2H crystals.^{17,49,50} However, the quantifiable reason for this dominating ET process remains unclear. Figure 3(a) shows the schematic illustration of the PL enhancement due to the proposed ET mechanism in the ReS₂-MoSe₂ HS. Upon photoexcitation with 2.33 eV (532 nm), hot excitons form above the bandgap, which thermalize to the lowest available excitonic level^{45,51} and subsequently recombine at the VB releasing photons of the energy equal to the optical bandgap. In ReS₂, the majority of excited state carriers nonradiatively recombine to the VB via phonon-mediated processes. We propose the following mechanism to explain the PL enhancement: in the presence of weaker interlayer CT process, more carriers in MoSe₂ layer resonantly excite in the excitonic level due to excitonic ET from the ReS₂ layer, giving a significant excess of radiative excitons in MoSe₂. Thus, the MoSe₂ PL emission is enhanced in the HS as shown in Figure 3(a). We excluded the possibility of the ReS₂ PL enhancement in the HS due to the fact that the HS PL emission shape and peak position perfectly matched with the MoSe₂ PL spectra (Figure S12).

To understand the nature of the ET process, we made several HSs with varying thickness of hBN layers inserted between the TMD layers (Figure 3(b) and S13). ET shows a distance dependence between the donor and acceptor as $1/d^n$, where n is a factor dependent on the systems dimensionality:⁵² n = 6 for 0D-to-0D dipole coupling, n = 4 for 0D-to-2D dipole coupling and n = 2 for 2D-to-2D dipole coupling.^{21,22} It is important to mention that, at shorter

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distances several processes such as charge tunneling through the hBN barrier, interlayer ET process and local impurity related opacity at the hBN-TMD interface could compete with each other. Thus, we considered to observe the pure ET effect from the maximum enhancement point in our experiment (Figure 3(c)). Specifically, at a distance of 13.5 and 14.7 nm we observed more than one order of magnitude higher PL enhancement factor of ~12.5 and 10.5, respectively. Beyond the maximum enhancement point, PL enhancement factor, which is considered to be directly proportional to ET, decreased with a $\sim 1/d^2$ dependency in our HS systems, which suggests that ET from ReS₂ to MoSe₂ occurred via 2Dto-2D dipole interaction.^{21–23} The fluctuation observed in the data within 15-25 nm distance (Figure 3(c)) could be the combined effect of varying material's property from sample-tosample and the change in coupling due to the rotational mismatch in our randomly stacked samples. We further confirmed the long-range dipole-dipole ET mechanism through a shortening of the excited state lifetime of the HS compared to the individual layers (Figure 3(d)). Compared to the isolated monolayers, which had PL lifetimes of \sim 5.41 and 2.06 ns for the acceptor (MoSe₂) and donor (ReS₂), respectively, the donor lifetime in the HS was shortened to ~620 ps (see Experimental Details and Table S1 in S.I. for the fitting details). ET occurs through a decreased donor fluorescence intensity and reduction of excited state lifetime accompanied by an increased acceptor fluorescence intensity. We find that there was a significant reduction of ReS₂ PL decay time in the HS as compared to the ReS₂ area alone (Figure 3(d)), which further proves that energy was transferred from ReS₂ to MoSe₂. To find the ET efficiency (E_{ET}) and ET rate (k_{ET}) in the ReS₂-MoSe₂ HS, we used the following equations:4,53,54

$$E_{ET} = 1 - \frac{t_{ReS2,HS}}{\tau_{ReS2}}$$
(2)
$$k_{ET} = \frac{1}{\tau_{ReS2}} - \frac{1}{\tau_{ReS2}}$$
(3)

 $\tau_{ReS2,HS}$ τ_{ReS2}

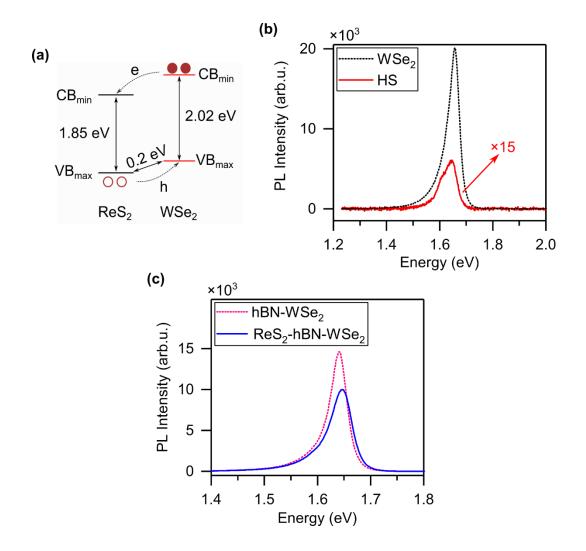


Figure 4. (a) Schematic illustration of type-II band alignment of ReS₂-WSe₂ HS. (b) PL measurement taken from the ReS₂-WSe₂ HS (Sample 4, S4) and 1L WSe₂ area. HS PL spectra shows massive quenching of WSe₂ emission. (c) PL spectra of the ReS₂-hBN-WSe₂ HS (Sample 5, S5) before and after transferring the top ReS₂ layer. After transferring the top ReS₂ layer, HS does not show an enhanced PL emission.

where $\tau_{ReS2, HS}$ is the ReS₂ PL lifetime in HS. By using the above-mentioned values in Equation 2 and 3 we calculate the ET efficiency and rate in the ReS₂-MoSe₂ HS to be ~70% and ~1.13 ns⁻¹ respectively. Interestingly, only 70% E_{ET} due to the bright excitonic coupling cannot results in the observed 360% PL enhancement (and 640% for the hBN encapsulated sample). One possibility could be that the ReS₂ 'short-lived' excitons are transferred before going through the nonradiative recombination process. Thus, the contribution from ReS₂ 'short-lived' bright states in the ET process cannot be ignored.

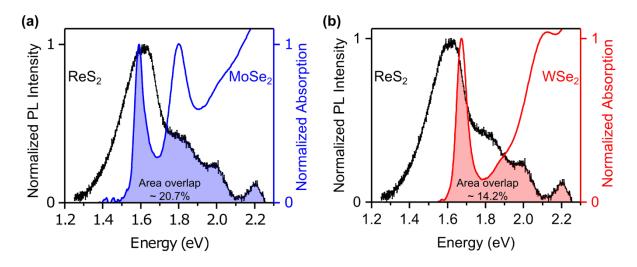


Figure 5. (a) and (b) Area overlaps between the normalized ReS_2 (donor) PL emission and the MoSe₂, WSe₂ (acceptor) absorption spectra at RT, respectively. The area overlaps for the MoSe₂ and WSe₂ system are ~20.7% and ~14.2%, respectively.

In order to check the resonant nature of the interlayer ET process, we replaced the MoSe₂ layer with WSe₂ (Sample 4, S4), which has about 80 meV larger optical bandgap than MoSe₂ (Figure 4 and S.I. Figure S14). The experimentally obtained ΔE_V between ReS₂ and WSe₂ from the KPFM measurement to be ~0.2 eV (Figure S15). Combining the ΔE_V value with WSe₂ electronic bandgap,⁵⁵ we found that 1L ReS₂-1L WSe₂ also form a similar type-II HS (Figure 4(a)), in agreement with previous reports. 15,20 PL measurements showed severely quenched HS PL emission (Figure 4(b)) due to interlayer CT being the dominant mechanism (Figure 4(a)), which is typical in type-II TMD HSs. It is worth mentioning here that in these ReS₂-MoSe₂ and ReS₂-WSe₂ HSs, the traditional type-II interlayer PL emissions are not visible due to the valley-forbidden dark excitonic nature (ReS₂ excitonic transition happens around the Γ valley in contrast with K valley in 2*H* materials).²⁰ To eliminate the interlayer CT process, we prepared a ReS₂-WSe₂ HS (Sample 5, S5) with few layers of hBN inserted in between. PL spectra of this HS did not lead to enhanced emission after placing the top ReS₂ layer (Figure 4(c)). The slightly reduced PL emission from the WSe₂ layer after placing the ReS₂ was mainly attributed to the absorption of the incoming photons from the top layer and scattering at the multiple interfaces. This was in stark contrast to the ReS₂-MoSe₂ and ReS₂-

hBN-MoSe₂ samples, where we observed PL enhancement regardless of the presence of the presence of a charge blocking hBN interlayer. It is evident that the ET from the ReS₂ layer was insufficient to enhance the PL emission from WSe₂ layer and the interlayer CT process dominated in this HS.

To further investigate the nature of the ET in TMDs, we examine the spectral overlap of the emission and absorption of donor and acceptors (Figure 5). The area overlaps for MoSe₂ and WSe₂ systems were ~20.7% and ~14.2%, respectively. It has been previously shown experimentally that $E_{\rm ET}$ increases with the increasing spectral overlap between the donor emission and acceptor absorption spectra.⁵⁶ Thus, based on the spectral overlaps, ET should be less efficient in the ReS₂-WSe₂ HS. However, the massive quenching of the WSe₂ PL emission from the HS proves that the ET rate cannot compete with the CT rate and donor relaxation rate in this configuration. This finally proves that nonradiative excitonic ET from ReS₂ *resonantly* excites radiative excitons in MoSe₂, resulting in the significant PL enhancement. This result also suggests that the traditional understanding may not be adequate enough to describe the ET process in these materials and future work will be required to develop a comprehensive understanding.

CONCLUSION

In summary, we have shown an interlayer resonant ET process in a type-II TMD HS *without* a charge blocking interlayer, resulting in 3.6 times MoSe₂ PL enhancement from the HS. We calculated the ET efficiency from our ReS₂-MoSe₂ HS to be ~70%, with a potential for increasing the overall efficiency in future work. The experimental findings suggest that resonant ET dominates over CT in ReS₂-MoSe₂ HSs, promoting radiative recombination in MoSe₂ at the HS region. Through insertion of a charge blocking hBN layer, we effectively suppress the competing CT process, achieving a maximum PL enhancement factor of 12.5 at a distance of 13.5 nm between the TMD layers. By varying the separation distance between

layers, we demonstrated the long-range ET has a distance dependence of $\sim 1/d^2$ for larger separation, indicating 2D dipole-to-2D dipole coupling between ReS₂ and MoSe₂ layers. Finally, we showed that by replacing the MoSe₂ layer with WSe₂, the resonant nature of ET broke, leading to interlayer CT dominating over the ET process, which resulted in a severely quenched WSe₂ PL emission from the HS. The ReS₂-MoSe₂ HS provides an opportunity to simultaneously study the ET and CT processes in TMD materials at ultrafast timescale in future work. We strongly believe that this work will help to discover more HS combinations that can exploit the normally parasitic nature of non-emissive 2D materials by increasing the PL emission intensity of 2D semiconducting emitters *via* ET, which can lead to improved TMD-based photovoltaic, optoelectronic, and photonic devices.

EXPERIMENTAL DETAILS

HS fabrication: hBN and TMD crystals were obtained from the National Institute of Materials Science, Japan; HQ Graphene, Netherlands and 2D Semiconductors, USA, respectively. hBN was exfoliated using the standard mechanical exfoliation technique. 1L TMD materials were exfoliated using the standard PDMS-based technique and carefully stacked on top of hBN flake using a homebuilt semi-automated transfer stage. ReS₂-MoSe₂ and ReS₂-WSe₂ HSs were annealed under high vacuum (\sim 5×10⁻⁶ Torr) at 250 °C for 4-6 hours to remove any polymer residue and make the monolayers in good contact with each other. **Characterization:** For the **AFM** measurement, we used Bruker Dimension ICON3-OS1707 in 'ScanAsyst' (peak force tapping) mode to obtain the highest resolution AFM image. We performed the **PL** and **Raman** spectroscopy measurement using Tokyo Instruments' Nanofinder 30 Microspectrometer. For low-temperature PL measurement the sample was loaded and cooled in a cryostat with continuous flow of liquid-nitrogen (N₂). For PL measurement the sample was illuminated using CW solid-state 532 nm laser with an average power of 5 μ W (spot size ~1 μ m) and focused by a 100x objective lens (N.A. 0.95). For the **absorption** spectroscopy analysis, we used Craic 20/30 PV Microspectro-photometer system with white light illumination at perpendicular direction on the sample surface. The transmitted light passing through a variable aperture were collected using a 100x objective lens (N.A. 0.9) before entering to the spectrum analyzer. The transmission spectra was converted to absorption spectra using equation, A% = 100 - T% (considering no reflection in the system).

We performed the **KPFM** measurement using the Bruker MultiMode 8 system with a platinum-iridium coated conductive tip. To obtain the high-resolution data we performed the measurement in frequency modulation (FM-KPFM) mode, which applies an AC voltage to the probe at very low frequency to obtain the electrostatic potential map of the sample surface.

TR-PL measurement was performed using a Spectra-Physics Matai XF-IMW femtosecond Ti:sapphire laser with tunable wavelengths from 710-920 nm, pulse width of 70 fs, and repetition rate of 80 MHz the 800 nm fundamental beam was passed through a second harmonic generator and pulse picker module to generate an excitation source with 400 nm wavelength and 4 MHz repetition rate. The spot size of the excitation beam on the sample surface was ~3 μ m, with an average power of 90 μ W. PL from the sample was collected through another 100x microscope objective (N.A. 0.70) and directed into a streak scope (Hamamatsu Photonics, C10627-03) coupled to a CCD. The instrument response function was determined by measuring the scattered laser light, which gave a temporal resolution of ~15 ps. After subtracting the instrumental response and the rise time, we fitted the normalized data from the MoSe₂ and ReS₂ monolayers area with a single-exponential decay function to get the faster decay component (intrinsic PL lifetime) . To obtain the ReS₂ lifetime in the HS, we fitted the HS data using the following equation:⁵⁷

$$f(x) = A_1 \left[exp(-(x - x_0)/\tau_{ReS2,HS}) - exp(-(x - x_0)/\tau_{MoSe2,HS}) \right] + A_2 \left[exp(-(x - x_0)/\tau_{MoSe2}) \right]$$

where A_1 , A_2 are constants, $\tau_{ReS2,HS}$ is the ReS₂ PL lifetime in the HS, $\tau_{MoSe2,HS}$ is the PL lifetime of excess charge in the HS MoSe₂ due to ET and τ_{MoSe2} is the MoSe₂ PL lifetime obtained from the 1L area.

AUTHOR INFORMATION

Author Contributions

A.K. conceived the project. A.K. and A.A.M. designed the experiments. A.K. fabricated the samples with help taken from O.K. and N.S.C. A.K. and A.A.M. characterized the samples. C.E.P. performed the TR-PL measurements and TMM calculations. K.M.D. provided the necessary funding. T.T. and K.W. provided the bulk hBN crystals for exfoliation. A.K. wrote the manuscript with feedback taken from all the co-authors.

Acknowledgements

A.K. acknowledges the useful discussion with Chakradhar Sahoo, and the help received from Joel Pérez Urquizo in setting up the cryo-PL measurements. This work was supported by the funding from the Femtosecond Spectroscopy Unit at the Okinawa Institute of Science and Technology Graduate University. K.W. and T.T. acknowledge support from the Elemental Strategy Initiative conducted by the MEXT, Japan (Grant Number JPMXP0112101001) and JSPS KAKENHI (Grant Numbers 19H05790 and JP20H00354).

ASSOCIATED CONTENT

Supporting Information Available: RT and LT PL spectra, details of TMM calculation, power dependent PL spectroscopy analysis, KPFM potential map and AFM height profile, Figure S1-S15; fitting parameters from the HS TR-PL data, Table S1.

Notes

The authors declare no competing financial interest.

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